AEAT-6600-XXX

10 to 16-Bit Programmable Angular Magnetic Encoder IC

Reliability Data Sheet

Description

The following cumulative test results have been obtained from testing performed at Avago Technologies Malaysia in accordance to JEDEC standards. Avago tests parts at the absolute maximum characteristics of the rated conditions recommended for the device. The actual performance obtained from Avago parts in your application depends on the electrical and environmental conditions but will probably be better than the performance outlined in Table 1.

Table 1. Life Tests

Test Name	Reference	Test Conditions	Units Tested	Unit Failed
High Temperature Operating Life	JESD22A-108	VDD=5.0V+/-0.5V, Ta= 125°C for 1000 hours	69	0
Temperature Humidity Bias	JESD22A-101	VDD=5.0V+/-0.5V, Ta= 85°C, RH=85% for 1000 hours	23	0
Low Temperature Operating Life	JESD22A-108	VDD=5.0V+/-0.5V, Ta= -40°C for 1000 hours	23	0

Table 2. Environmental Tests

Test Name	Reference	Test Conditions	Units Tested	Unit Failed
Temperature Cycling	JESD22A-104	-40°C to 125°C, 15min dwell time, 5 min transfer time for 1000 cycles	75	0
High Temperature Storage Life	JESD22A-103	Ta= 125°C for 1000 hours	75	0

Table 3. Electrical Tests

Test Name	Reference	Test Conditions	Units Tested	Unit Failed
Human Body Model ESD	JESD22-A114	Up to +/- 2000V applied to all pins versus ground	12	0
Machine Model ESD	JESD22-A115	Up to +/- 200V applied to all pins versus ground	12	0
Latch-up	JESD78	Class 1 (Ta=25°C)	9	0

For product information and a complete list of distributors, please go to our web site: **www.avagotech.com**

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